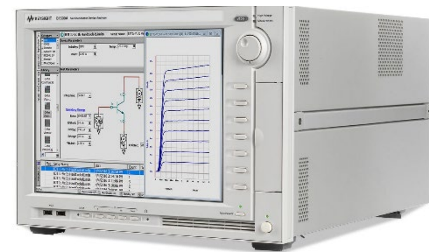
FLYER

# *Advanced Material and Device Characterization*

## Using the Keysight B1500A Parameter Analyzer

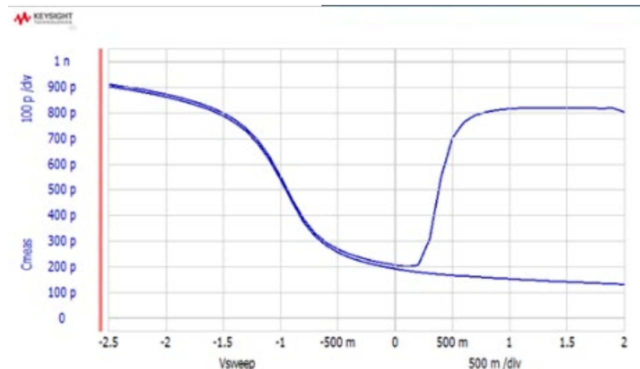
12:00 pm – 1:30 pm
November 2, 2023
BRK 1001 conference room

**Lunch provided**: please RSVP to Neil Dilley ndilley@purdue.edu



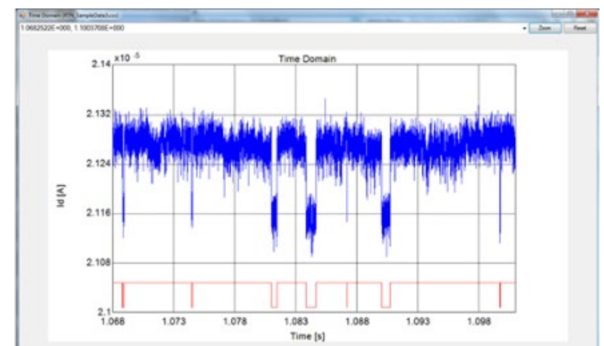
## Topics Covered:

- Material & Device Measurement Overview
- Current/Voltage Measurement Basics
- Capacitance Measurement
- Fast and Fast Pulsed IV Measurement




## Learn Measurement Fundamentals

This seminar will begin by covering the basics of current-voltage (IV) measurement, including source/measure unit (SMU) operation, making correct connections for low-current measurements, performing 4-wire (Kelvin) measurements, and selecting optimal measurement settings. It will then cover the fundamentals of capacitance-voltage (CV) measurements, including the basics of LCR meter operation and considerations when making on-wafer CV measurements. Finally, since high-speed measurements are increasingly important for modern semiconductor devices, the seminar will conclude with a discussion of high-speed pulsed measurement techniques and their applications.

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